

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/568,191	TOMIKAWA ET AL.	
Examiner		Art Unit		Page 1 of 2
Phillip E. Decker		3749		

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-3,059,167 A	10-1962	BYLES THEODORE A	322/25
*	B US-3,106,665 A	10-1963	BYLES THEODORE A	361/709
*	C US-5,045,971 A	09-1991	Ono et al.	361/704
*	D US-5,311,398 A	05-1994	Schirmer et al.	361/704
*	E US-5,403,782 A	04-1995	Dixon et al.	29/827
*	F US-5,461,542 A	10-1995	Kosak et al.	361/710
*	G US-5,953,207 A	09-1999	Aakalu et al.	361/690
*	H US-6,055,158 A	04-2000	Pavlovic, Slobodan	361/704
*	I US-6,282,092 B1	08-2001	Okamoto et al.	361/704
*	J US-2001/0026430 A1	10-2001	Onizuka et al.	361/103
*	K US-6,341,066 B1	01-2002	Murowaki et al.	361/707
*	L US-2003/0045137 A1	03-2003	Yamane et al.	439/76.2
*	M US-6,704,201 B2	03-2004	Kasuga, Nobuyuki	361/704

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	EP 1780094 A1	05-2007	European Patent	KIM et al.	B62D 05/04
O	JP 2007118919 A	05-2007	Japan	KIM et al.	
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination TOMIKAWA ET AL.	
		Examiner Phillip E. Decker	Art Unit 3749	Page 2 of 2

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,724,627 B2	04-2004	Onizuka et al.	361/704
*	B US-6,785,139 B2	08-2004	Onizuka et al.	361/704
*	C US-2005/0047095 A1	03-2005	Tomikawa et al.	361/715
*	D US-6,924,985 B2	08-2005	Kawakita et al.	361/715
*	E US-7,189,082 B2	03-2007	Fukushima et al.	439/76.2
*	F US-2007/0195504 A1	08-2007	Tomikawa et al.	361/715
*	G US-7,632,110 B2	12-2009	Kanou et al.	439/76.2
*	H US-7,813,134 B2	10-2010	Katsuro, Hajime	361/714
*	I US-7,877,868 B2	02-2011	Tomikawa et al.	29/841
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.